

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Electrostatics –
Part 4-7: Standard test methods for specific applications – Ionization**

**Électrostatique –
Partie 4-7: Méthodes d'essai normalisées pour des applications spécifiques –
Ionisation**



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ELECTROSTATICS –**Part 4-7: Standard test methods for specific applications –
Ionization****FOREWORD**

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International Standard IEC 61340-4-7 has been prepared by IEC technical committee 101: Electrostatics.

This second edition cancels and replaces the first edition, published in 2010, and constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- the use of contacting plate voltage measurements in addition to the previous non-contacting plate voltage measurements has been added. Charged plate monitors (CPMs) using this technology have been in use in the industry for many years.

The text of this standard is also based on the following documents:

FDIS	Report on voting
101/521/FDIS	101/524/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 61340 series, published under the general title *Electrostatics*, can be found on the IEC website.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC website under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
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INTRODUCTION

Grounding is the primary method used to limit static charge when protecting electrostatic discharge sensitive items in the work environment. However, grounding methods are not effective in removing static charges from the surfaces of non-conductive (insulative) or isolated conductive materials. Air ionization techniques, by means of ionizer systems, can be utilized to reduce this charge.

The preferred way of evaluating the ability of an ionizer to neutralize a static charge is to directly measure the rate of charge decay. Charges to be neutralized may be located on insulators as well as on isolated conductors. It is difficult to charge an insulator reliably and repeatably. Charge neutralization is more easily evaluated by measuring the rate of decay of the voltage of an isolated conductive plate. The measurement of this decay should not interfere with or change the nature of the actual decay. Four practical methods of air ionization are addressed in this document:

- a) radioactive emission;
- b) high-voltage corona from a.c. electric fields;
- c) high-voltage corona from d.c. electric fields;
- d) soft X-ray emission.

This part of IEC 61340 provides test methods and procedures that can be used when evaluating ionization equipment. The objective of the test methods is to generate meaningful, reproducible data. The test methods are not meant to be a recommendation for any particular ionizer configuration. The wide variety of ionizers, and the environments within which they are used, will often require test methods different from those described in this document. Users of this document should be prepared to adapt the test methods as required to produce meaningful data in their own application of ionizers.

Similarly, the test conditions chosen in this document do not represent a recommendation for acceptable ionizer performance. There is a wide range of item sensitivities to static charge. There is also a wide range of environmental conditions affecting the operation of ionizers. Performance specifications should be agreed upon between the user and manufacturer of the ionizer in each application. Users of this document should be prepared to establish reasonable performance requirements for their own application of ionizers.

Annex B provides a method for measuring capacitance of the isolated conductive plate.